


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/708,305	LEE, TIEK-NYEN	
	Examiner	Art Unit	
	Steven M. Marsh	3632	

SEARCHED			
Class	Subclass	Date	Examiner
updated	search	4/25/2006	SMM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR